## Search Notes



10599107

Applicant(s)/Patent Under Reexamination

TAGAWA ET AL.

Examiner

Son T Nguyen

Art Unit

## **SEARCHED**

Class	Subclass	Date	Examiner
47	1.01P,1.01R,1.7	4/8/10	stn
111	114,104,105	4/8/10	stn
414	416.09,416.11	4/8/10	stn
198	468.6	4/8/10	stn

## **SEARCH NOTES**

Search Notes	Date	Examiner
Foreign IPC search, see printouts	4/8/10	stn
Consulted with primaries J.Keenan (class 414) and J.Bidwell (class 198)	4/8/10	stn
previous search updated	11/172010	stn

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		
47	1.01P	11/17/2010	stn		

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U.S. Patent and Trademark Office Part of Paper No.: 20101117